


<b>Search Notes</b> 	<b>Application/Control No.</b> 10752642	<b>Applicant(s)/Patent Under Reexamination</b> NAKAMURA ET AL.
	<b>Examiner</b> CHRIS C CHU	<b>Art Unit</b> 2815

SEARCHED			
Class	Subclass	Date	Examiner
257	E21.584, E21.582, E21.174, 758, 751, 762 an 763d	6/30/09	C.C.

SEARCH NOTES		
Search Notes	Date	Examiner
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; FPRS; and IBM_TDB;	6/30/09	C.C.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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